

Search Notes



Application/Control No.

10/550,202

Examiner

Sang Y. Paik

Applicant(s)/Patent under Reexamination

TANAKA ET AL.

Art Unit

3742

SEARCHED

Class	Subclass	Date	Examiner
392	416- 418		
219	402-		
	414,		
	483-		
	495		
108	724		
	725		
updated		7/19/07	1P

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EST-RET SEARCHED	1/30/07	1P